

EAST Search History

Ref #	Hits	Search Query	D8s	Default Operator	Plurals	Time Stamp
L9	8	(local near flare).clm.	US-PGPUB	OR	ON	2009/05/19 15:33

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L6	132	703/6.ccls. and @pd>="20081101"	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2009/05/19 14:39
L7	68	(local near flare)	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2009/05/19 15:05

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S16	1953	716/19.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2009/05/19 15:57



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... been developed for correcting line width variations due to midrange flare with a

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D Nam, E Lee, S Jung, YS Kang, G Yeo, J Lee, H Cho ... - Proceedings of SPIE, 2002 - link.aip.org

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Page 1. 4B-1 **Local Flare** Effects and Correction in ArF Lithography Teruyoshi Yao,

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... In this paper, the **local flare** values are measured using dose-to-clear method and

CD measurement method in order to confirm the exposure tool condition. ...

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WA Sinclair - The Elms: Breeding, Conservation, and Disease Management, 2000 - books.google.com

... in New York State, observed since 1971, has had the following characteristics (Lanier

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L Terslev, S Torp-Pedersen, E Qvistgaard, H ... - Acta Radiologica, 2003 - informaworld.com

... Most often, the intra-articular injection is given as a supplement to systemic treatment of RA during a **local flare** up of the disease. ...

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Test photomask, flare evaluation method, and flare compensation method

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... in a zonal shape which becomes a flare causing pattern forming a light transmission region which surrounds the line pattern and causes **local flare** to occur on ...

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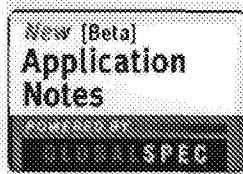
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